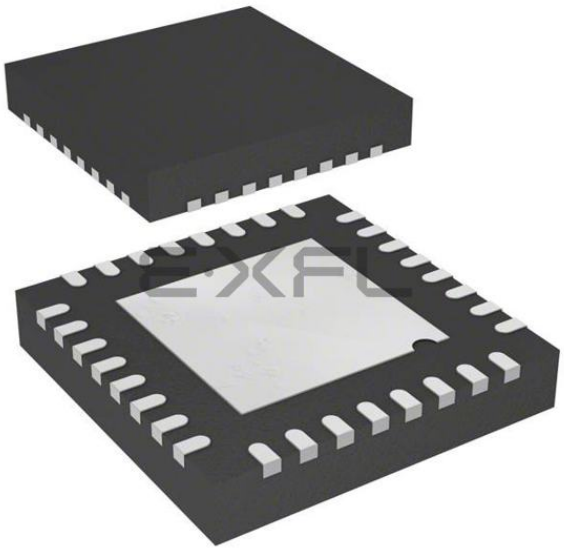

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	STM8A
Core Size	8-Bit
Speed	16MHz
Connectivity	I²C, IrDA, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, POR, PWM, WDT
Number of I/O	30
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	1.65V ~ 3.6V
Data Converters	A/D 22x12b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	32-VFQFN Exposed Pad
Supplier Device Package	32-VFQFPN (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8al3146ucx

Contents

2 Description

The medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x devices are members of the STM8AL automotive ultra-low-power 8-bit family. The medium-density STM8AL3xxx family operates from 1.8 V to 3.6 V (down to 1.65 V at power down) and is available in the -40 to +85°C and -40 to +125°C temperature ranges.

The medium-density STM8AL3xxx ultra-low-power family features the enhanced STM8 CPU core providing increased processing power (up to 16 MIPS at 16 MHz) while maintaining the advantages of a CISC architecture with improved code density, a 24-bit linear addressing space and an optimized architecture for low power operations.

The family includes an integrated debug module with a hardware interface (SWIM) which allows non-intrusive In-Application debugging and ultrafast Flash programming.

All medium-density STM8AL3xxx microcontrollers feature embedded data EEPROM and low power low-voltage single-supply program Flash memory.

They incorporate an extensive range of enhanced I/Os and peripherals.

The modular design of the peripheral set allows the same peripherals to be found in different ST microcontroller families including 32-bit families. This makes any transition to a different family very easy, and simplified even more by the use of a common set of development tools.

Two different packages are proposed which include 32 and 48 pins. Depending on the device chosen, different sets of peripherals are included.

All STM8AL3xxx ultra-low-power products are based on the same architecture with the same memory mapping and a coherent pinout.

3.3 Reset and supply management

3.3.1 Power supply scheme

The STM8AL313x/4x/6x and STM8AL3L4x/6x require a 1.65 V to 3.6 V operating supply voltage (V_{DD}). The external power supply pins must be connected as follows:

- V_{SS1}; V_{DD1} = 1.8 to 3.6 V, down to 1.65 V at power down: external power supply for I/Os and for the internal regulator. Provided externally through V_{DD1} pins, the corresponding ground pin is V_{SS1}.
- $V_{SSA;}$ V_{DDA} = 1.8 V to 3.6 V, down to 1.65 V at power down: external power supplies for analog peripherals (minimum voltage to be applied to V_{DDA} is 1.8 V when the ADC1 is used). V_{DDA} and V_{SSA} must be connected to V_{DD1} and V_{SS1}, respectively.
- V_{SS2}; V_{DD2} = 1.8 V to 3.6 V, down to 1.65 V at power down: external power supplies for I/Os. V_{DD2} and V_{SS2} must be connected to V_{DD1} and V_{SS1}, respectively.
- V_{REF+}; V_{REF-} (for ADC1): external reference voltage for ADC1. Must be provided externally through V_{REF+} and V_{REF-} pin.
- V_{REF+} (for DAC): external voltage reference for DAC must be provided externally through V_{REF+}.

3.3.2 Power supply supervisor

The STM8AL313x/4x/6x and STM8AL3L4x/6x have an integrated ZEROPOWER power-on reset (POR)/power-down reset (PDR), coupled with a brownout reset (BOR) circuitry. At power-on, BOR is always active, and ensures proper operation starting from 1.8 V. After the 1.8 V BOR threshold is reached, the option byte loading process starts, either to confirm or modify default thresholds, or to disable BOR permanently (in which case, the V_{DD} min value at power down is 1.65 V).

Five BOR thresholds are available through option bytes, starting from 1.8 V to 3 V. To reduce the power consumption in Halt mode, it is possible to automatically switch off the internal reference voltage (and consequently the BOR) in Halt mode. The device remains under reset when V_{DD} is below a specified threshold, $V_{POR/PDR}$ or V_{BOR}, without the need for any external reset circuit.

The STM8AL313x/4x/6x and STM8AL3L4x/6x feature an embedded programmable voltage detector (PVD) that monitors the V_{DD}/V_{DDA} power supply and compares it to the V_{PVD} threshold. This PVD offers 7 different levels between 1.85 V and 3.05 V, chosen by software, with a step around 200 mV. An interrupt can be generated when V_{DD}/V_{DDA} drops below the V_{PVD} threshold and/or when V_{DD}/V_{DDA} is higher than the V_{PVD} threshold. The interrupt service routine can then generate a warning message and/or put the MCU into a safe state. The PVD is enabled by software.

3.13 Timers

The medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x devices contain one advanced control timer (TIM1), two 16-bit general purpose timers (TIM2 and TIM3) and one 8-bit basic timer (TIM4).

All the timers can be served by DMA1.

Table 3 compares the features of the advanced control, general-purpose and basic timers.

Table 3. Timer feature comparison

Timer	Counter resolution	Counter type	Prescaler factor	DMA1 request generation	Capture/compare channels	Complementary outputs
TIM1	16-bit	up/down	Any integer from 1 to 65536	Yes	3 + 1	3
TIM2			Any power of 2 from 1 to 128		2	None
TIM3						
TIM4	8-bit	up	Any power of 2 from 1 to 32768		0	

3.13.1 TIM1 - 16-bit advanced control timer

This is a high-end timer designed for a wide range of control applications. With its complementary outputs, dead-time control and center-aligned PWM capability, the field of applications is extended to motor control, lighting and half-bridge driver.

- 16-bit up, down and up/down auto reload counter with 16-bit prescaler
- Three independent capture/compare channels (CAPCOM) configurable as input capture, output compare, PWM generation (edge and center aligned mode) and single pulse mode output.
- One additional capture/compare channel which is not connected to an external I/O
- Synchronization module to control the timer with external signals
- Break input to force timer outputs into a defined state
- Three complementary outputs with adjustable dead time
- Encoder mode
- Interrupt capability on various events (capture, compare, overflow, break, trigger)

3.13.2 16-bit general purpose timers

- 16-bit auto reload (AR) up/down-counter
- 7-bit prescaler adjustable to fixed power of 2 ratios (1…128)
- Two individually configurable capture/compare channels
- PWM mode
- Interrupt capability on various events (capture, compare, overflow, break, trigger)
- Synchronization with other timers or external signals (external clock, reset, trigger and enable)

Table 5. Medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x pin description (continued)

Pin number			Pin name	Type	I/O level	Input			Output			Main function (after reset)	Default alternate function
LQFP48	VFQFPN32	LQFP32				floating	wpu	Ext. interrupt	High sink/source	OD	PP		
38	26	26	PC1(5)/I2C1_SCL	I/O	FT	X	-	X	-	T(7)		Port C1	I2C1 clock
41	27	27	PC2/USART1_RX/ LCD_SEG22/ADC1_IN6/ COMP1_INP/VREFINT	I/O	TT(3)	X	X	X	HS	X	X	Port C2	USART1 receive / LCD segment 22 / ADC1_IN6 / Comparator 1 positive input / Internal voltage reference output
42	28	28	PC3/USART1_TX/ LCD_SEG23(2)/ ADC1_IN5/COMP1_INP/ COMP2_INM	I/O	TT(3)	X	X	X	HS	X	X	Port C3	USART1 transmit / LCD segment 23 / ADC1_IN5 / Comparator 1 positive input / Comparator 2 negative input
43	29	29	PC4/USART1_CK/ I2C1_SMB/CCO/ LCD_SEG24(2)/ ADC1_IN4/COMP2_INM/ COMP1_INP	I/O	TT(3)	X	X	X	HS	X	X	Port C4	USART1 synchronous clock / I2C1_SMB / Configurable clock output / LCD segment 24 / ADC1_IN4 / Comparator 2 negative input / Comparator 1 positive input
44	30	30	PC5/OSC32_IN /*[SPI1_NSS]*(4)/ *[USART1_TX]*(4)	I/O	-	X	X	X	HS	X	X	Port C5	LSE oscillator input / *[SPI1 master/slave select] / [USART1 transmit]*
45	31	31	PC6/OSC32_OUT/ *[SPI1_SCK]*(4)/ *[USART1_RX]*(4)	I/O	-	X	X	X	HS	X	X	Port C6	LSE oscillator output / *[SPI1 clock] / [USART1 receive]*
46	-	-	PC7/LCD_SEG25(2)/ ADC1_IN3/COMP2_INM/ COMP1_INP	I/O	TT(3)	X	X	X	HS	X	X	Port C7	LCD segment 25 /ADC1_IN3/ Comparator negative input / Comparator 1 positive input

Table 8. I/O port hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 500F	Port D	PD_ODR	Port D data output latch register	0x00
0x00 5010		PD_IDR	Port D input pin value register	0xXX
0x00 5011		PD_DDR	Port D data direction register	0x00
0x00 5012		PD_CR1	Port D control register 1	0x00
0x00 5013		PD_CR2	Port D control register 2	0x00
0x00 5014	Port E	PE_ODR	Port E data output latch register	0x00
0x00 5015		PE_IDR	Port E input pin value register	0xXX
0x00 5016		PE_DDR	Port E data direction register	0x00
0x00 5017		PE_CR1	Port E control register 1	0x00
0x00 5018		PE_CR2	Port E control register 2	0x00
0x00 5019	Port F	PF_ODR	Port F data output latch register	0x00
0x00 501A		PF_IDR	Port F input pin value register	0xXX
0x00 501B		PF_DDR	Port F data direction register	0x00
0x00 501C		PF_CR1	Port F control register 1	0x00
0x00 501D		PF_CR2	Port F control register 2	0x00

Table 9. General hardware register map

Address	Block	Register label	Register name	Reset status
0x00 501E to 0x00 5049	Reserved area (44 bytes)			
0x00 5050	Flash	FLASH_CR1	Flash control register 1	0x00
0x00 5051		FLASH_CR2	Flash control register 2	0x00
0x00 5052		FLASH _PUKR	Flash program memory unprotection key register	0x00
0x00 5053		FLASH _DUKR	Data EEPROM unprotection key register	0x00
0x00 5054		FLASH _IAPSR	Flash in-application programming status register	0x00

Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 52E0	TIM4	TIM4_CR1	TIM4 control register 1	0x00
0x00 52E1		TIM4_CR2	TIM4 control register 2	0x00
0x00 52E2		TIM4_SMCR	TIM4 slave mode control register	0x00
0x00 52E3		TIM4_DER	TIM4 DMA1 request enable register	0x00
0x00 52E4		TIM4_IER	TIM4 interrupt enable register	0x00
0x00 52E5		TIM4_SR1	TIM4 status register 1	0x00
0x00 52E6		TIM4_EGR	TIM4 event generation register	0x00
0x00 52E7		TIM4_CNTR	TIM4 counter	0x00
0x00 52E8		TIM4_PSCR	TIM4 prescaler register	0x00
0x00 52E9		TIM4_ARR	TIM4 auto-reload register	0x00
0x00 52EA to 0x00 52FE	Reserved area (21 bytes)			
0x00 52FF	IRTIM	IR_CR	Infrared control register	0x00
0x00 5300 to 0x00 533F	Reserved area (64 bytes)			
0x00 5340	ADC1	ADC1_CR1	ADC1 configuration register 1	0x00
0x00 5341		ADC1_CR2	ADC1 configuration register 2	0x00
0x00 5342		ADC1_CR3	ADC1 configuration register 3	0x1F
0x00 5343		ADC1_SR	ADC1 status register	0x00
0x00 5344		ADC1_DRH	ADC1 data register high	0x00
0x00 5345		ADC1_DRL	ADC1 data register low	0x00
0x00 5346		ADC1_HTRH	ADC1 high threshold register high	0x0F
0x00 5347		ADC1_HTRL	ADC1 high threshold register low	0xFF
0x00 5348		ADC1_LTRH	ADC1 low threshold register high	0x00
0x00 5349		ADC1_LTRL	ADC1 low threshold register low	0x00
0x00 534A		ADC1_SQR1	ADC1 channel sequence 1 register	0x00
0x00 534B		ADC1_SQR2	ADC1 channel sequence 2 register	0x00
0x00 534C		ADC1_SQR3	ADC1 channel sequence 3 register	0x00
0x00 534D		ADC1_SQR4	ADC1 channel sequence 4 register	0x00
0x00 534E		ADC1_TRIGR1	ADC1 trigger disable 1	0x00
0x00 534F		ADC1_TRIGR2	ADC1 trigger disable 2	0x00
0x00 5350		ADC1_TRIGR3	ADC1 trigger disable 3	0x00
0x00 5351		ADC1_TRIGR4	ADC1 trigger disable 4	0x00

Table 25. Total current consumption and timing in active-halt mode at V_{DD} = 1.65 V to 3.6 V (continued)

Symbol	Parameter	Conditions (1)			Typ	Max(2)	Unit
$I_{DD(AH)}$	Supply current in Active-halt mode	LSE external clock (32.768 kHz) (7)	LCD OFF(8)	T_A = -40 °C to 25 °C	0.50	1.20	µA
				T_A = 85 °C	0.90	2.10	
				T_A = 125 °C	4.80	11.00	
			LCD ON (static duty/ external V_{LCD}) (4)	T_A = -40 °C to 25 °C	0.85	1.90	
				T_A = 85 °C	1.30	3.20	
				T_A = 125 °C	5.00	12.00	
			LCD ON (1/4 duty/ external V_{LCD}) (5)	T_A = -40 °C to 25 °C	1.50	2.50	
				T_A = 85 °C	1.80	4.20	
				T_A = 125 °C	5.70	14.00	
			LCD ON (1/4 duty/ internal V_{LCD}) (6)	T_A = -40 °C to 25 °C	3.40	7.60	
				T_A = 85 °C	3.90	9.20	
				T_A = 125 °C	6.30	15.20	
$I_{DD(WUFAH)}$	Supply current during wakeup time from Active-halt mode (using HSI)	-	-	-	2.40	-	mA
$t_{WU\_HSI(AH)}$ (9) (10)	Wakeup time from Active-halt mode to Run mode (using HSI)	-			4.70	7.00	µs
$t_{WU\_LSI(AH)}$ (9) (10)	Wakeup time from Active-halt mode to Run mode (using LSI)	-			150.0	-	

1. No floating I/O, unless otherwise specified.
2. Guaranteed by characterization results.
3. RTC enabled. Clock source = LSI.
4. RTC enabled, LCD enabled with external V_{LCD} = 3 V, static duty, division ratio = 256, all pixels active, no LCD connected.
5. RTC enabled, LCD enabled with external V_{LCD}, 1/4 duty, 1/3 bias, division ratio = 64, all pixels active, no LCD connected.
6. LCD enabled with internal LCD booster V_{LCD} = 3 V, 1/4 duty, 1/3 bias, division ratio = 64, all pixels active, no LCD connected.
7. Oscillator bypassed (LSEBYP = 1 in CLK_ECKCR). When configured for external crystal, the LSE consumption ($I_{DD\ LSE}$) must be added. Refer to *Table 33*.
8. RTC enabled. Clock source = LSE.
9. Wakeup time until start of interrupt vector fetch.
   The first word of interrupt routine is fetched 4 CPU cycles after t_{WU}.
10. ULP=0 or ULP=1 and FWU=1 in the PWR_CSR2 register.

Table 38. Flash program memory

Symbol	Parameter	Conditions	Min	Max	Unit
T_{WE}	Temperature for writing and erasing	-	-40	125	°C
N_{WE}	Flash program memory endurance (erase/write cycles)(1)	T_A = 25 °C	1000	-	cycles
t_{RET}	Data retention time	T_A = 25 °C	40	-	years
		T_A = 55 °C	20	-	

1. The physical granularity of the memory is four bytes, so cycling is performed on four bytes even when a write/erase operation addresses a single byte.

Data memory

Table 39. Data memory

Symbol	Parameter	Conditions	Min	Max	Unit
T_{WE}	Temperature for writing and erasing	-	-40	125	°C
N_{WE}	Data memory endurance (erase/write cycles)(1)	T_A = 25 °C	300 k	-	cycles
		T_A = -40 to 125 °C	100 k(2)	-	
t_{RET}	Data retention time	T_A = 25 °C	40(2)(3)	-	years
		T_A = 55 °C	20(2)(3)	-	

1. The physical granularity of the memory is four bytes, so cycling is performed on four bytes even when a write/erase operation addresses a single byte.
2. More information on the relationship between data retention time and number of write/erase cycles is available in a separate technical document.
3. Retention time for 256B of data memory after up to 1000 cycles at 125 °C.

9.3.6 I/O current injection characteristics

As a general rule, current injection to the I/O pins, due to external voltage below V_{SS} or above V_{DD} (for standard pins) should be avoided during normal product operation. However, in order to give an indication of the robustness of the microcontroller in cases when abnormal injection accidentally happens, susceptibility tests are performed on a sample basis during device characterization.

Functional susceptibility to I/O current injection

While a simple application is executed on the device, the device is stressed by injecting current into the I/O pins programmed in floating input mode. While current is injected into the I/O pin, one at a time, the device is checked for functional failures.

The failure is indicated by an out of range parameter: ADC error, out of spec current injection on adjacent pins or other functional failure (for example reset, oscillator frequency deviation, LCD levels, etc.).

The test results are given in the following table.

Figure 20. Typical V_{IL} and V_{IH} vs V_{DD} (true open drain I/Os)

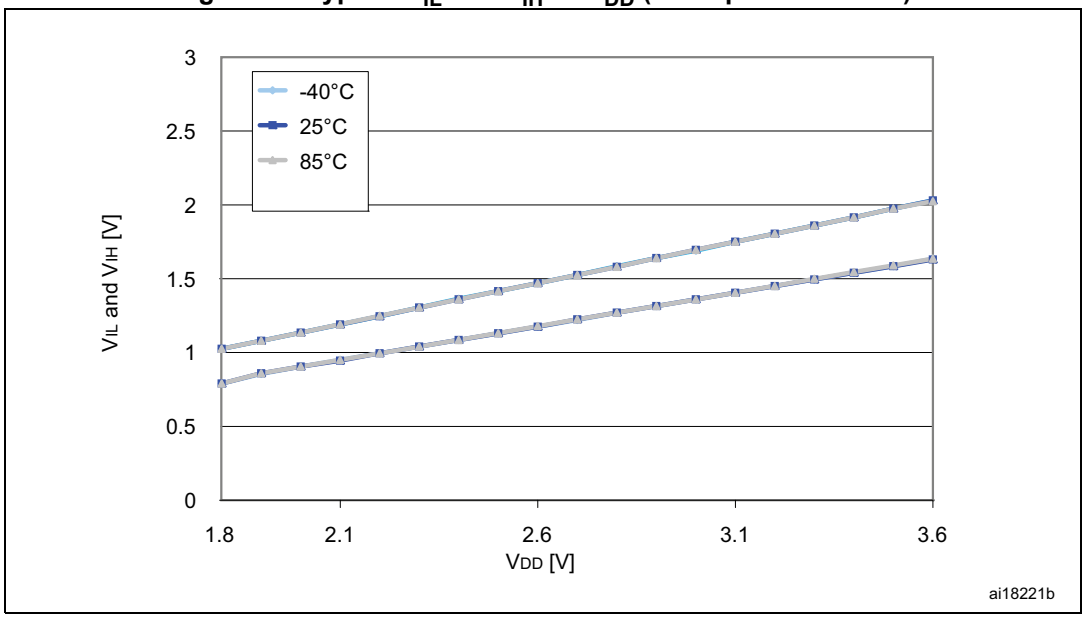


Figure 21. Typical pull-up resistance R_{PU} vs V_{DD} with $V_{IN}=V_{SS}$

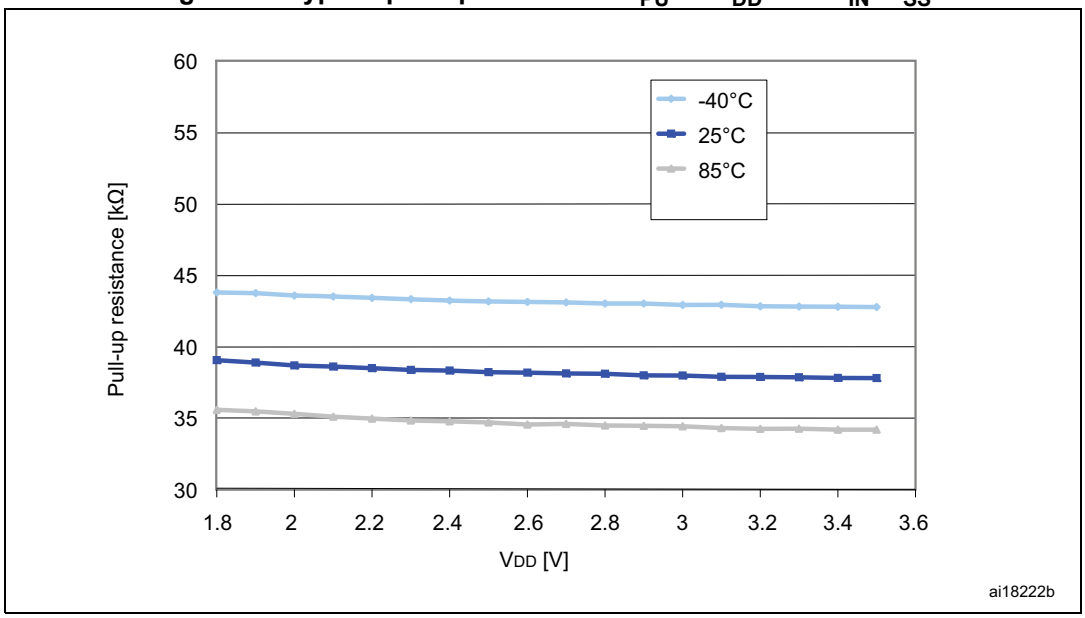


Figure 22. Typical pull-up current I_{pu} vs V_{DD} with $V_{IN}=V_{SS}$

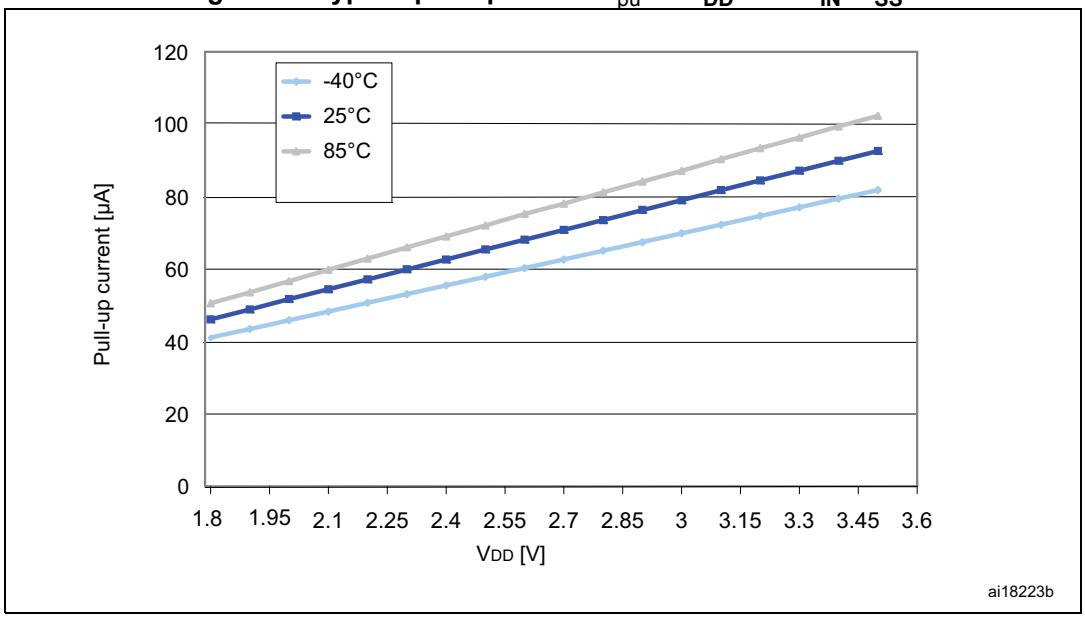
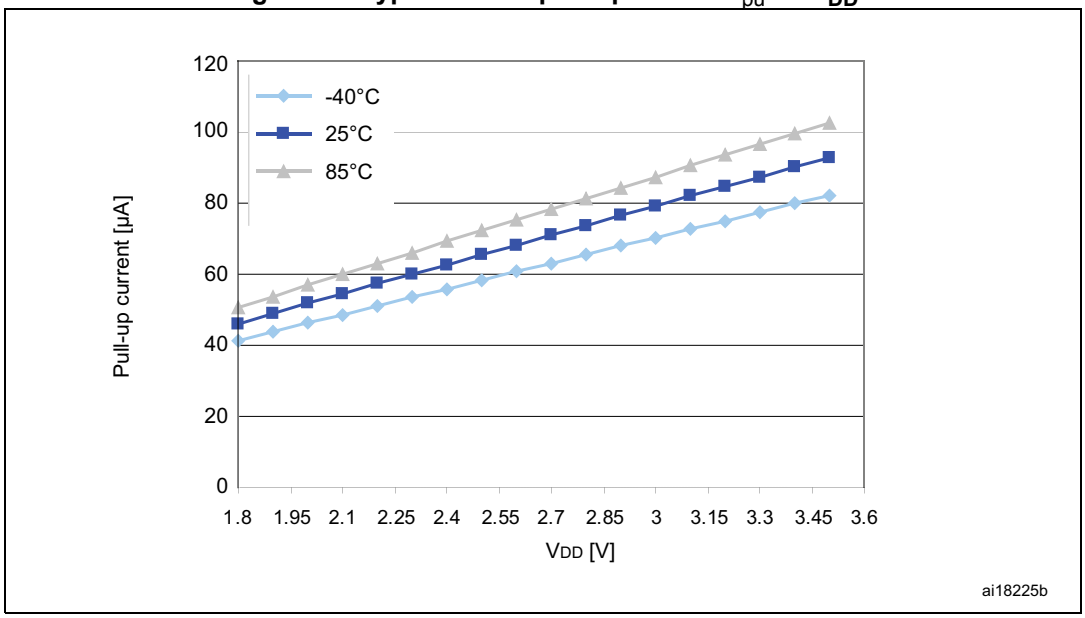


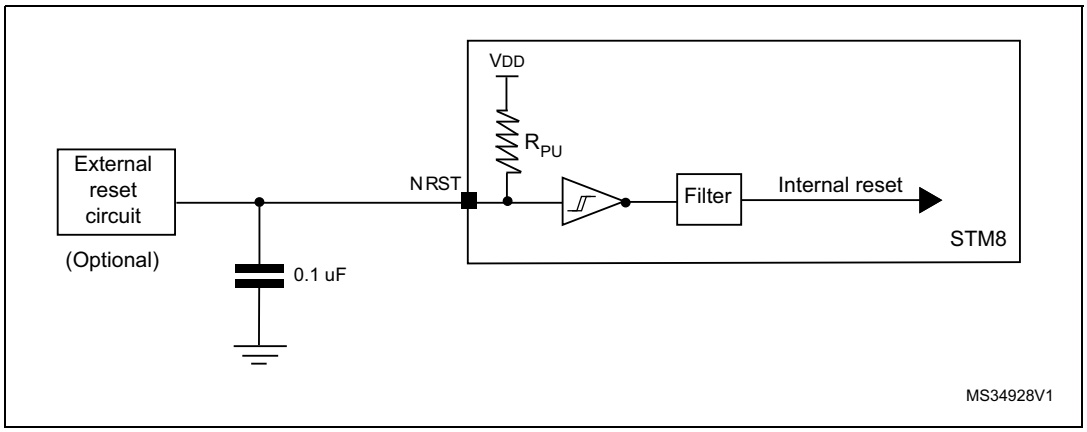
Figure 30. Typical NRST pull-up current I_{pu} vs V_{DD}



The reset network shown in *Figure 31* protects the device against parasitic resets. The user must ensure that the level on the NRST pin can go below the V_{IL} max. level specified in *Table 45*. Otherwise the reset is not taken into account internally.

For power consumption sensitive applications, the external reset capacitor value can be reduced to limit the charge/discharge current. If the NRST signal is used to reset the external circuitry, attention must be paid to the charge/discharge time of the external capacitor to fulfill the external devices reset timing conditions. The minimum recommended capacity is 10 nF.

Figure 31. Recommended NRST pin configuration



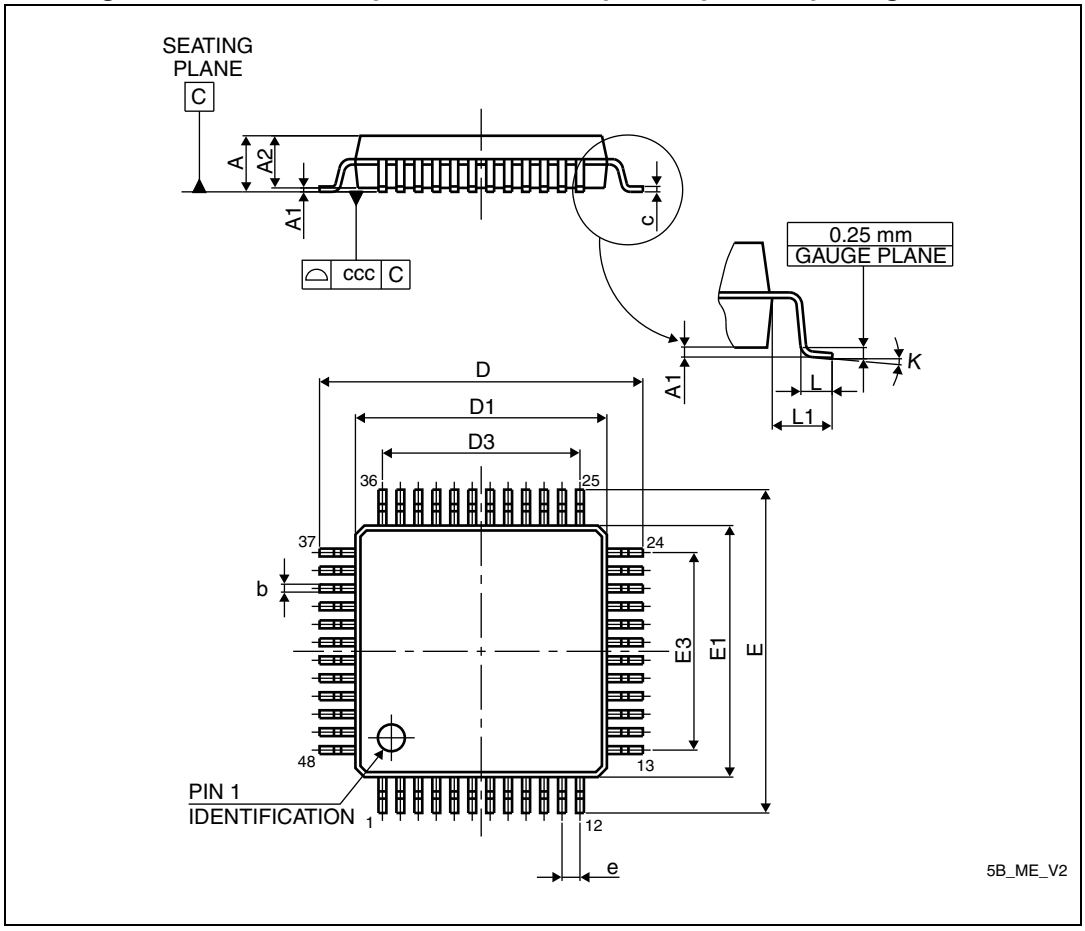
10 Package information

10.1 ECOPACK

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK® is an ST trademark.

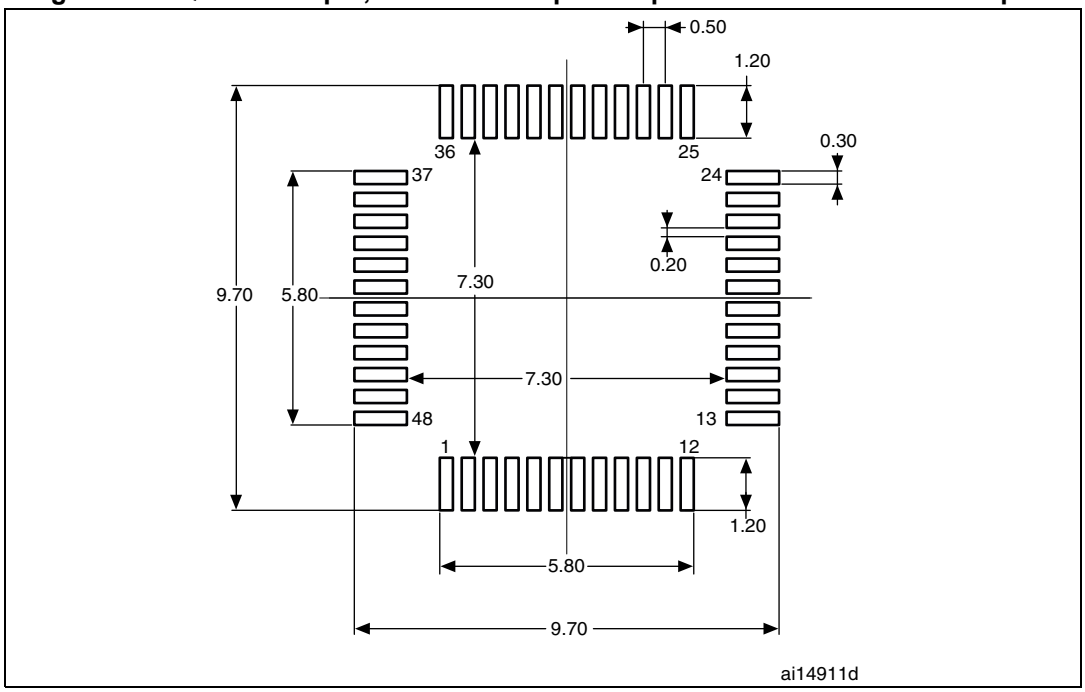
10.2 LQFP48 package information

Figure 41. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package outline



1. Drawing is not to scale.

Figure 42. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat recommended footprint

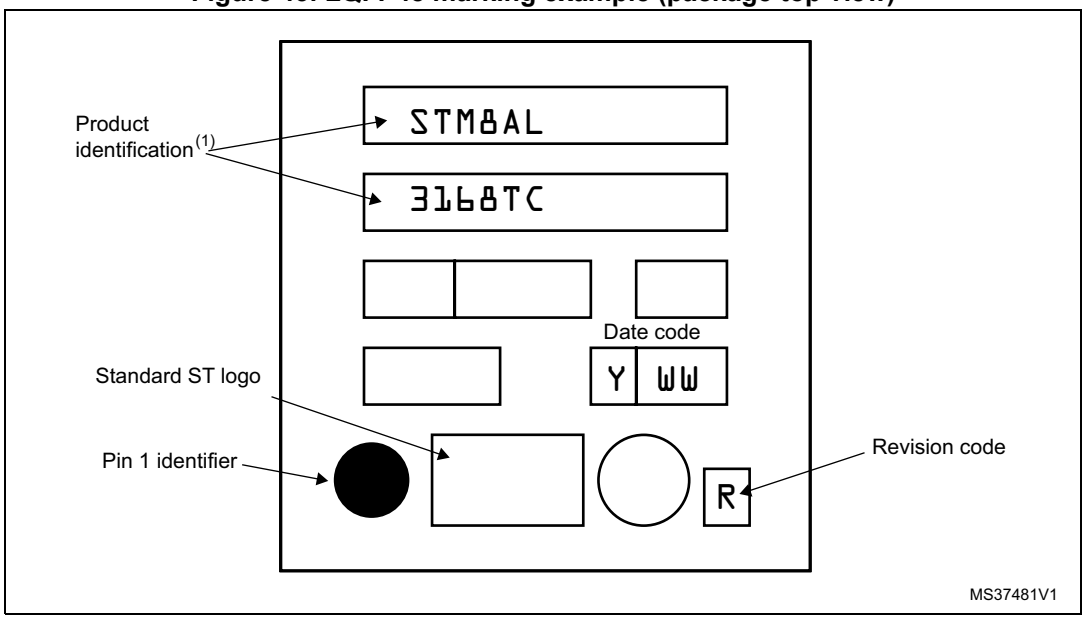


1. Dimensions are expressed in millimeters.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

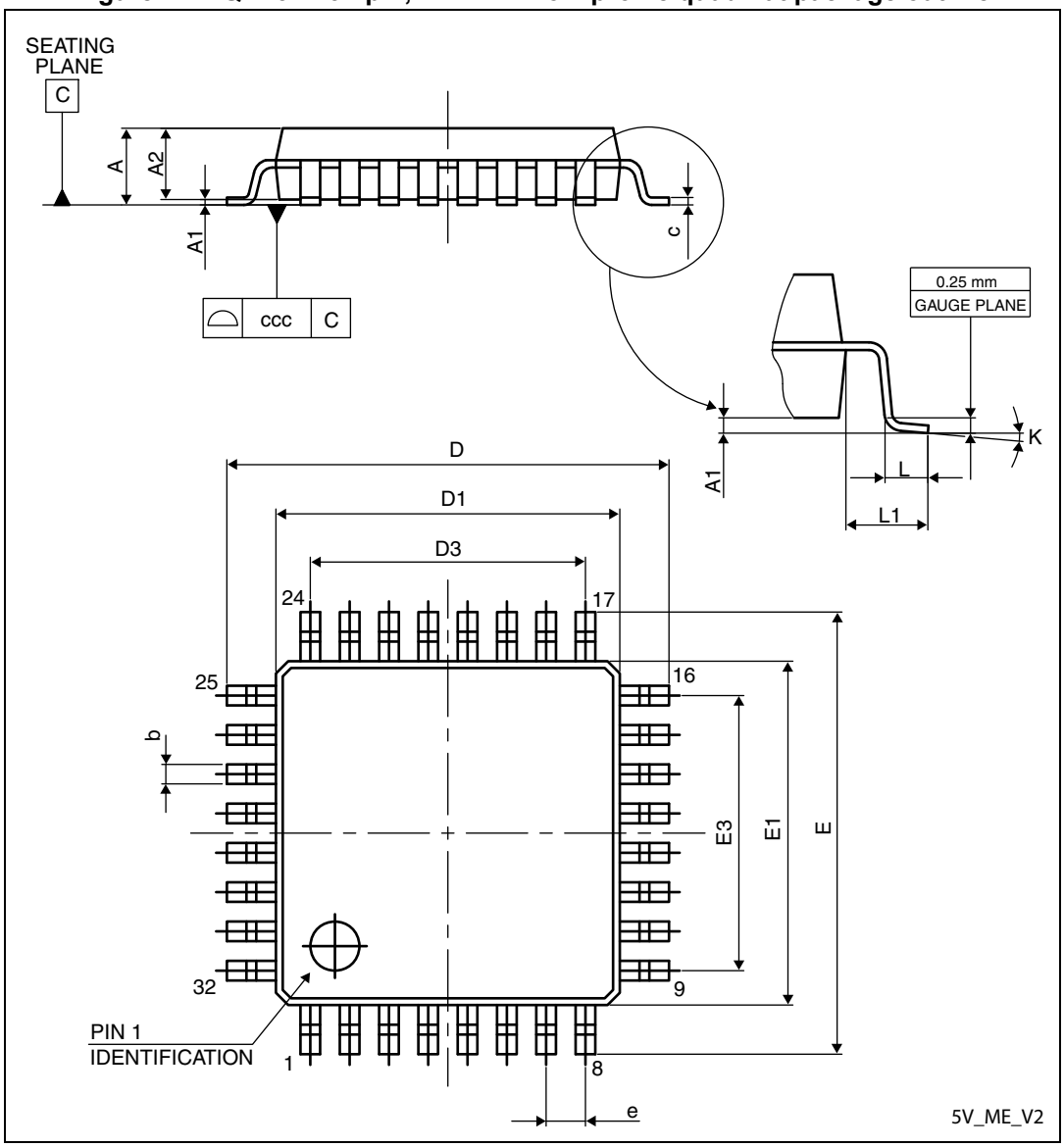
Figure 43. LQFP48 marking example (package top view)



1. Parts marked as “ES” or “E” are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST’s Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.

10.3 LQFP32 package information

Figure 44. LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat package outline



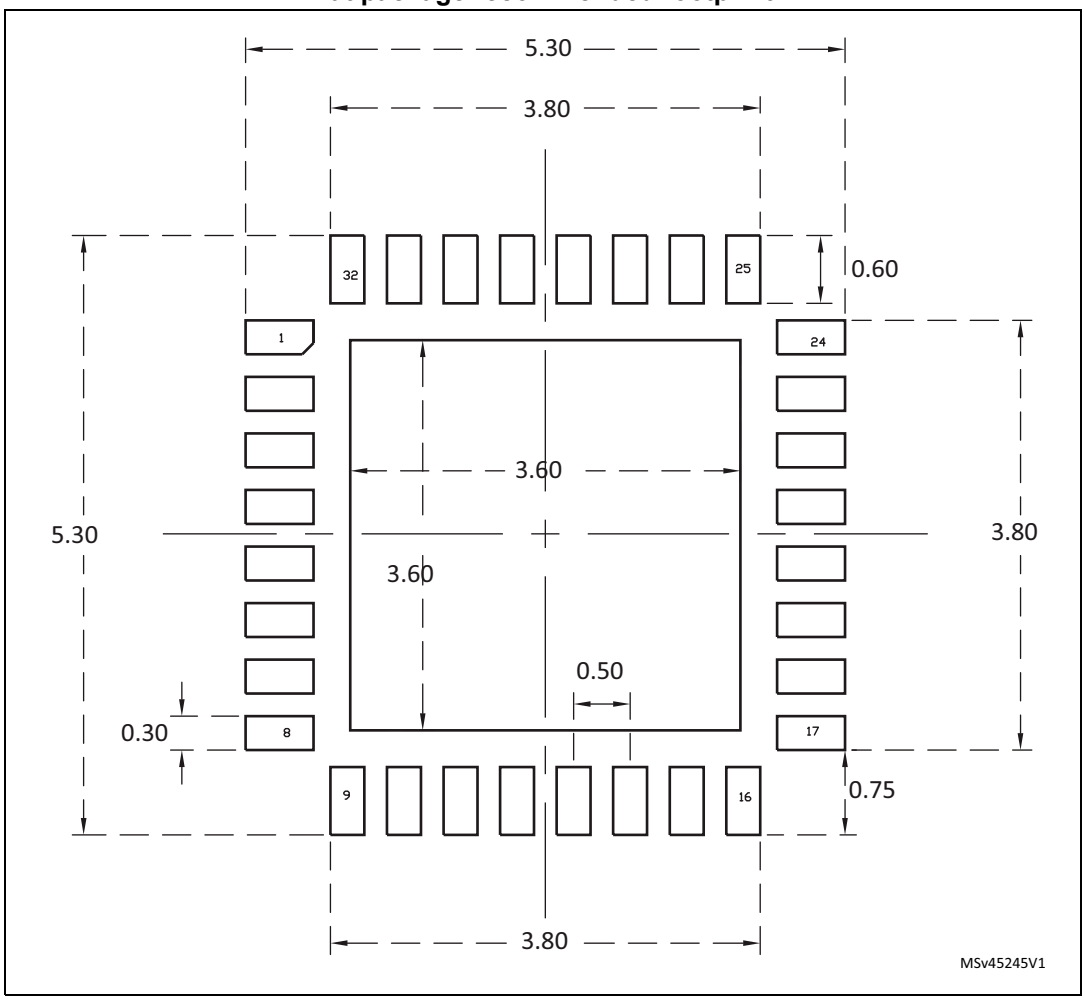
1. Drawing is not to scale.

Table 67. VFQFPN32 - 32-pin, 5x5 mm, 0.5 mm pitch very thin profile fine pitch quad flat package mechanical data

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	0.800	0.900	1.000	0.0315	0.0354	0.0394
A1	0.000	0.020	0.050	0.0000	0.0008	0.0020
A3	-	0.200	-	-	0.0079	-
b	0.180	0.250	0.300	0.0071	0.0098	0.0118
D	4.850	5.000	5.150	0.1909	0.1969	0.2028
D2	3.500	3.600	3.700	0.1378	0.1417	0.1457
E	4.850	5.000	5.150	0.1909	0.1969	0.2028
E2	3.500	3.600	3.700	0.1378	0.1417	0.1457
e	-	0.500	-	-	0.0197	-
L	0.300	0.400	0.500	0.0118	0.0157	0.0197
ddd	-	-	0.050	-	-	0.0020

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 48. VFQFPN32 - 32-pin, 5x5 mm, 0.5 mm pitch very thin profile fine pitch quad flat package recommended footprint



1. Dimensions are expressed in millimeters.

Table 69. Document revision history (continued)

Date	Revision	Changes
03-Mar-2014	5	Changed the document status to Datasheet - Production data to reflect the device maturity. Corrected the data memory size in the *Features*. Updated the package assignment in *Table 2: Medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x low-power device features and peripheral counts*
13-May-2015	6	Updated: – the product names in the document headers and on the cover page, – *Section 1: Introduction*, – the captions of *Figure 3: STM8AL31x8T 48-pin pinout (without LCD)*, *Figure 4: STM8AL3Lx8T 48-pin pinout (with LCD)*, *Figure 5: STM8AL31x6T 32-pin pinout (without LCD)*, *Figure 6: STM8AL3Lx6T 32-pin pinout (with LCD)*, – *Table 6: Flash and RAM boundary addresses*, – I_{LEAK_HSE} maximum value in *Table 32: HSE oscillator characteristics*,I_{LEAK_LSE} maximum value in *Table 33: LSE oscillator characteristics*, – *Table 54*, *Table 57*, *Table 58*, *Table 59* with a footnote for Max values not tested in production, – *Section 9.3.15: EMC characteristics*, – *Section 10.2: LQFP48 package information*, – *Section 10.3: LQFP32 package information*, – *Figure 50: Medium-density STM8AL313x/4x/6x and STM8AL3L4x/6x ordering information scheme*. Added: – *Figure 43: LQFP48 marking example (package top view)*, – *Figure 46: LQFP32 marking example (package top view)*. Moved *Section 10.5: Thermal characteristics* to *Section 10: Package information*.